

Search Notes

Application/Control No.

10/623,320

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

ICHIKAWA ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/2/2007	NT
348/211.1 - 211.14 (text search - see search history printout)	3/7/2007	NT
348/207.1 - 207.11 (text search - see search history printout)	3/7/2007	NT
text search class 714 and all databases listed above	3/7/2007	NT